

Indirect Studies of Electroweakly Interacting Particles at 100 TeV Hadron Colliders

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May 6, 2019 @ Pheno

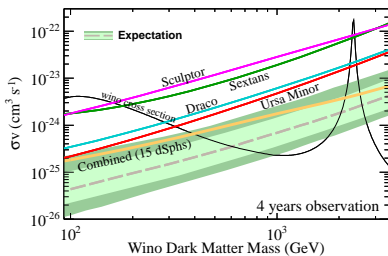
SC, Yohei Ema, and Takeo Moroi
PLB **789** (2019) 106 [arXiv:1810.07349]
Tomohiro Abe, SC, Yohei Ema, and Takeo Moroi
[arXiv:1904.11162]

ElectroWeakly Interacting Massive Particle (EWIMP)

- EWIMP : massive particle with non-zero weak charges
 - Good dark matter (DM) candidate ... “WIMP miracle”
- ex) Higgsino, Wino, Minimal Dark Matter

Detection methods of EWIMPs

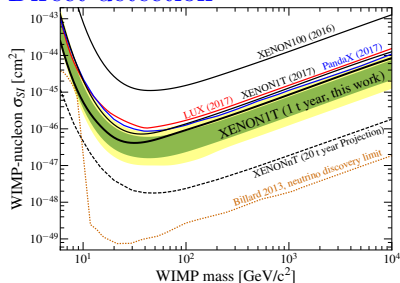
Indirect detection



B. Bhattacharjee⁺ '14

Disappearing track search @ LHC

Direct detection



XENON1T '18

(mono-X search)

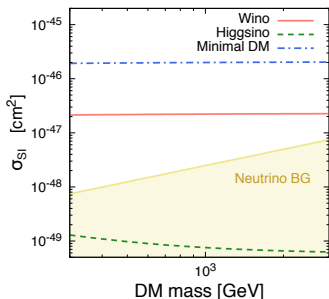
Difficulty with Higgsino

Higgsino detection may be **difficult** (model dependent)

Indirect / Direct detection

Higgsino annihilation / scattering cross section is **too small**

J. Hisano⁺ '15



Disappearing track search

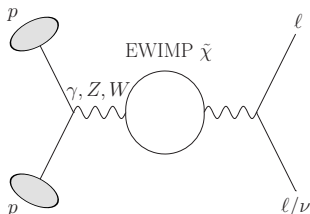
Tiny gaugino fraction (= “almost pure” Higgsino) makes Higgsino short lifetime with $c\tau \ll \mathcal{O}(\text{cm})$

How can we search for short lifetime Higgsino?

Invitation : indirect study using colliders

Today I introduce

Indirect search with $l\bar{l}/l\nu$ production @ 100 TeV collider



Features

- ✓ Independent of EWIMP lifetime \Rightarrow **Good for Higgsino**
- ✓ Clean, tremendous events : 2 energetic leptons (+ jet)
 \Rightarrow **Signal shape** as a func. of lepton inv. mass is usable
 - ✓ to control systematic errors
 - ✓ to determine EWIMP mass and charges

Neutral current (NC) / Charged current (CC)

Parton level scattering amplitude for $q^a \bar{q}^b \rightarrow \ell \ell$ (NC) / $\ell \nu$ (CC)

$$\mathcal{M} = \underbrace{\text{Diagram 1}}_{\mathcal{M}_{\text{SM}}} + \underbrace{\text{Diagram 2}}_{\mathcal{M}_{\text{EWIMP}}} + \dots$$

Cross section for **fixed** $q^2 \equiv s'$

$$|\mathcal{M}|^2 = |\mathcal{M}_{\text{SM}}|^2 + 2\Re[\mathcal{M}_{\text{SM}}\mathcal{M}_{\text{EWIMP}}^*] + \dots$$

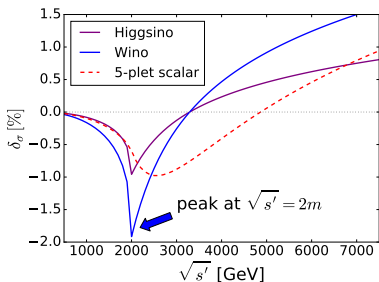
$$\frac{d\sigma^{ab}}{d\sqrt{s'}} \equiv \frac{d\sigma_{\text{SM}}^{ab}}{d\sqrt{s'}} + \frac{d\sigma_{\text{EWIMP}}^{ab}}{d\sqrt{s'}} + \dots$$

Define the size of correction

$$\delta_{\sigma}^{ab}(\sqrt{s'}) \equiv \frac{d\sigma_{\text{EWIMP}}^{ab}/d\sqrt{s'}}{d\sigma_{\text{SM}}^{ab}/d\sqrt{s'}}$$

Cross section correction from EWIMPs

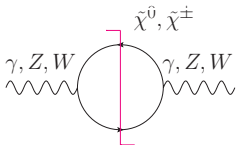
Plot of δ_{σ}^{ab} for $q^a \bar{q}^b \rightarrow \ell \nu$ (CC) with $m = 1$ TeV EWIMPs



Peak structure at $\sqrt{s'} = 2m$ plays an important role

“threshold effect”

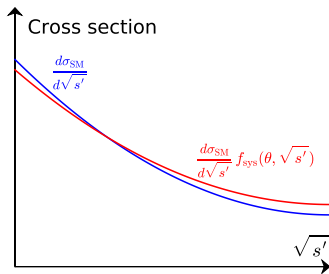
Same for $l\bar{l}$ (NC)



Idea of fitting based analysis

Systematic errors may modify theoretical prediction $\frac{d\sigma_{SM}}{d\sqrt{s'}}$

- luminosity error
- beam energy error
- choice of renormalization scale
- choice of factorization scale
- choice of PDF
- etc ...



Idea of fitting based analysis

Absorb above errors into additional parameters θ
 (Similar to “side band analysis”)

Fitting based analysis

Consider number of events binned by $\sqrt{s'}$

– $\mathbf{x} = \{x_i\}$: prediction for SM (i : label of bin)

– $\tilde{\mathbf{x}} = \{\tilde{x}_i\}$: experimental data (now assume SM+EWIMP)

Define new theoretical prediction $\tilde{x}_i(\boldsymbol{\theta})$

$$\tilde{x}_i(\boldsymbol{\theta}) \equiv x_i f_{\text{sys},i}(\boldsymbol{\theta}) \quad ; \quad f_{\text{sys},i}(\mathbf{0}) = 1$$

CDF collaboration '08

– We checked **systematic errors successfully absorbed** into $\boldsymbol{\theta}$

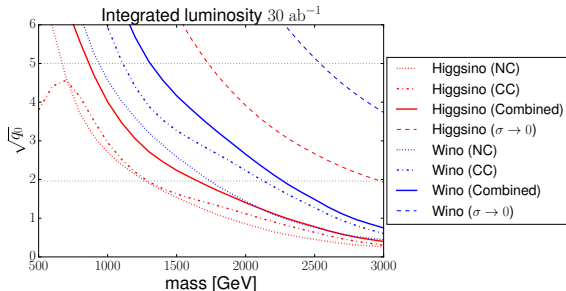
Use a test statistic q_0 that tests the validity of SM

$$q_0 \sim \min_{\boldsymbol{\theta}} \sum_{i:\text{bin}} \frac{(\tilde{x}_i - \tilde{x}_i(\boldsymbol{\theta}))^2}{\tilde{x}_i(\boldsymbol{\theta})} \sim \chi^2(1)$$

Result: detection reach

Solid lines : upper bound on the sensitivity

Dashed lines : when statistical errors dominate systematic ones

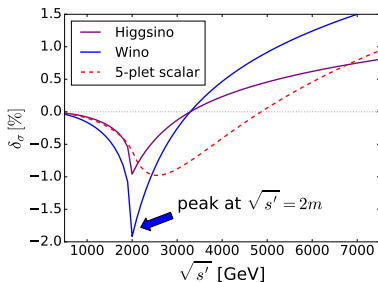
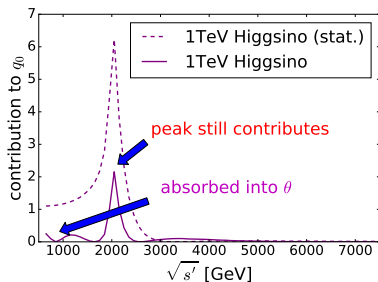


	Higgsino	Wino
5σ	850 GeV	1.6 TeV
5σ (stat.)	1.7 TeV	2.5 TeV

It is important to understand systematic errors

Which bin contributes a lot?

Plot contribution to q_0 from each bin

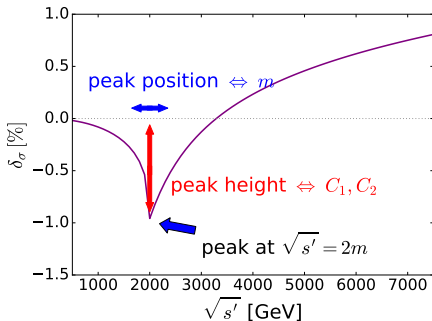


Peak structure at $\sqrt{s'} \sim 2m$ is not fitted.
It is very important for detection.

Determination of EWIMP properties

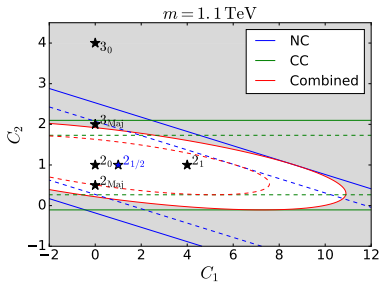
For $SU(2)_L$ n -plet Dirac fermion with $U(1)_Y$ charge Y

$$C_2 \equiv \frac{1}{6}(n^3 - n) \quad ; \quad C_1 \equiv 2nY^2$$



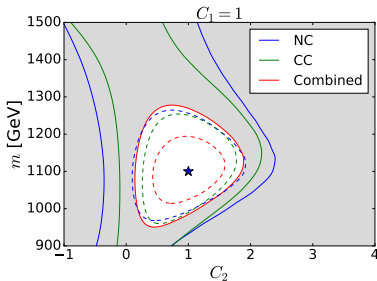
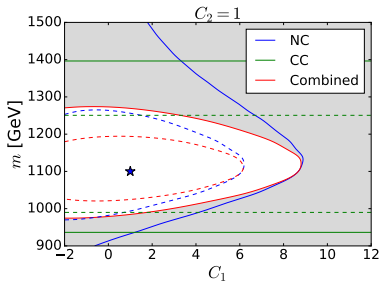
We can extract m, C_1, C_2 from peak structure

Determination of (m, C_1, C_2) for 1.1 TeV Higgsino



Solid (Dotted) : 2σ (1σ)
 n_Y : $SU(2)_L$ n -plet
 with $U(1)_Y$ charge Y

- Only doublet is allowed
- $m \sim 1.1 \text{ TeV} \pm 100 \text{ GeV}$



Conclusion

I introduced a way for probing EWIMPs with precision measurement at 100 TeV colliders

I also introduced fitting based analysis, where systematic errors are absorbed into the fit function

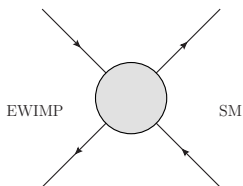
- ✓ All the errors we have considered are fitted well
- ✓ Strong discovery potential for short lifetime Higgsino
850 GeV (1.7 TeV) at 5σ (95% C.L.)
- ✓ The peak structure of the EWIMP effect can also be used to determine the EWIMP properties (mass, charge)

Peak at $\sqrt{s'} = 2m$ is important for all the analysis

Backup slides

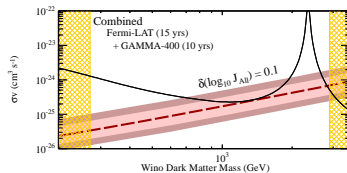
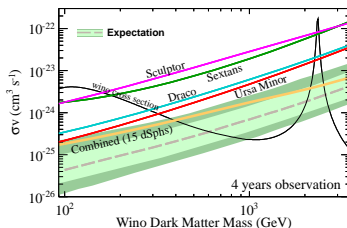
Indirect detection of DM

EWIMP annihilation into SM
 γ channel best for EWIMP



✓ Wino & MDM
Already exclude
 $m_{\tilde{W}} < 400 \text{ GeV}, \sim 2 \text{ TeV}$

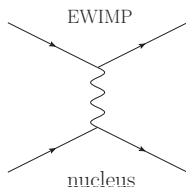
✗ Higgsino
Cross section too small



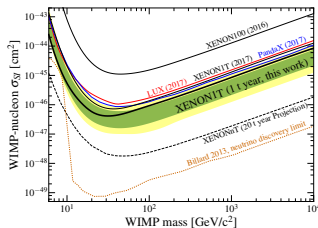
B. Bhattacharjee⁺ '14

Direct detection of DM

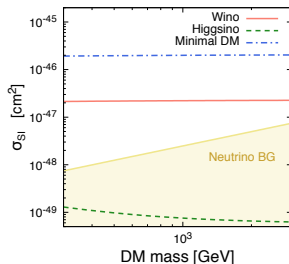
Collision btw. DM and nucleus
Look for recoiled nuclei



- ✓ Wino & MDM
Region of future interest
- ✗ Higgsino
Cross section below ν BG



XENON1T '18



J. Hisano+ '15

Higgsino phenomenology

chargino neutralino mass difference

H. Fukuda, et al. [1703.09675]

$$\begin{aligned}\Delta m_+ &= \Delta m_{\text{rad}} + \Delta m_{\text{tree}} \\ \Delta m_{\text{rad}} &\simeq \frac{1}{2} \alpha_2 m_Z s_W^2 \left(1 - \frac{3m_Z}{2\pi m_{\tilde{\chi}^\pm}} \right) \simeq 355 \text{MeV}, \\ \Delta m_{\text{tree}} &\simeq \frac{v^2}{8|\mu|} [|X| \Delta_X + \sin 2\beta \Re(Y)] \sim 1 \text{GeV} \left| \frac{\mu}{M_i} \right|,\end{aligned}$$

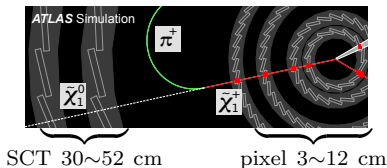
with $X, Y = \mu^*(g_1^2/M_1 \pm g_2^2/M_2)$, $\Delta_X = \sqrt{1 - \sin^2 \theta_X \sin^2 2\beta}$

$$c\tau \simeq 0.7 \text{cm} \left[\left(\frac{\Delta m_+}{340 \text{MeV}} \right)^3 \sqrt{1 - \frac{m_\pi^2}{\Delta m_+^2}} \right]^{-1}$$

Production at collider

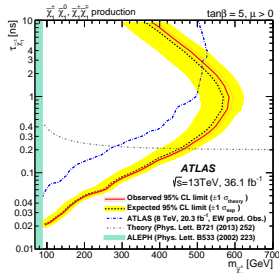
Difficulty : event recognition

- disappearing track \Leftarrow strict, **requires long life time**



ATLAS [1712.02118]

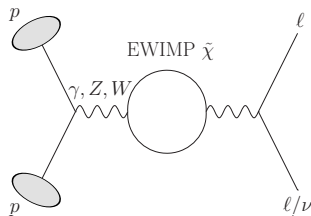
CMS [1804.07321]



- ✓ $c\tau_{\tilde{W}} \sim 6\text{ cm}, m_{\tilde{W}} < 460\text{ GeV}$ excluded
- ✓ $c\tau_{\tilde{H}} \sim 1\text{ cm}, m_{\tilde{H}} < 152\text{ GeV}$ excluded for **pure Higgsino**
- ✗ **Higgsino mixed with gaugino** : $c\tau \ll \mathcal{O}(\text{cm})$
- mono-X search : recognize events with initial state radiation
no bound on Higgsino @ LHC

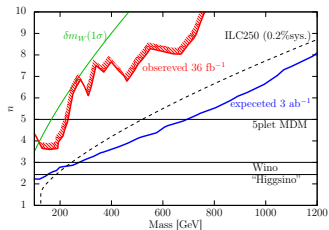
Studies of indirect search at collider

- ✓ Applicable to Higgsino independent of life time



Previous analysis:

- D. S. M. Alves, et al. [1410.6810] @ LHC, 100 TeV
- C. Gross, et al. [1602.03877] @ LHC
- M. Farina, et al. [1609.08157] @ LHC
- K. Harigaya, et al. [1504.03402] @ lepton collider
- S. Matsumoto, et al. [1711.05449] @ HL-LHC



S. Matsumoto, et al.

Up to HL-LHC era

Only a part of allowed region probed

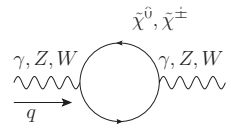
- $m_{\tilde{W}} < 300 \text{ GeV} \ll 3 \text{ TeV}$
- $m_{\tilde{H}} < 150 \text{ GeV} \ll 1 \text{ TeV}$

Let's consider future
100 TeV collider
to cover all the regions!!

Vacuum polarization effect from EWIMP

Assume all new physics except EWIMPs are decoupled

Consider vacuum polarization effect from EWIMPs


$$\propto i(q^2 g^{\mu\nu} - q^\mu q^\nu) f(q^2/m^2)$$

f is a loop function

$$f(x) = \begin{cases} \frac{1}{16\pi^2} \int_0^1 dy y(1-y) \ln(1 - y(1-y)x - i0) & \text{(Fermion)} \\ \frac{1}{16\pi^2} \int_0^1 dy (1-2y)^2 \ln(1 - y(1-y)x - i0) & \text{(Scalar)} \end{cases}$$

Effective lagrangian (Note: q^2/m^2 expansion NOT performed)

$$\mathcal{L}_{\text{eff}} = \mathcal{L}_{\text{SM}} + C_1 g'^2 B_{\mu\nu} f\left(-\frac{\partial^2}{m^2}\right) B^{\mu\nu} + C_2 g^2 W_{\mu\nu}^a f\left(-\frac{D^2}{m^2}\right) W^{a\mu\nu}$$

Group theoretical factors C_1, C_2

$SU(2)_L$ n -plet with $U(1)_Y$ charge Y contributes

$$C_1 = \frac{\kappa}{8} n Y^2, \quad C_2 = \frac{\kappa}{96} (n^3 - n),$$

$$\kappa = \begin{cases} 16 & \text{(Dirac fermion)} \\ 8 & \text{(Weyl or Majorana fermion)} \\ 2 & \text{(complex scalar)} \\ 1 & \text{(real scalar)} \end{cases}$$

For popular EWIMPs

	Higgsino	Wino	5-fermion ($Y = 0$)	7-scalar ($Y = 0$)
C_1	1	0	0	0
C_2	1	2	10	7/2

From parton-level to proton cross section

Proton cross section at $\sqrt{s} = 100$ TeV can be obtained using

$$\frac{dL_{ab}}{dm_{\ell\ell}} \equiv \frac{1}{s} \int_0^1 dx_1 dx_2 f_a(x_1) f_b(x_2) \delta\left(\frac{m_{\ell\ell}^2}{s} - x_1 x_2\right)$$

$f_a(x)$: parton distribution function (PDF) for a

$$\frac{d\sigma}{dm_{\ell\ell}} = \sum_{a,b} \frac{dL_{ab}}{dm_{\ell\ell}} \frac{d\sigma^{ab}}{dm_{\ell\ell}}$$

Indirect study with precision measurement

Task : Detect $\mathcal{O}(1)\%$ effect through precision measurement

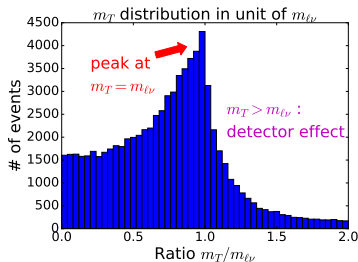
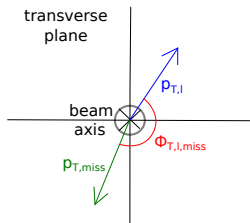
Method : Use functional form of $\delta_\sigma(\sqrt{s'})$

Difficulty :

- For $\ell\ell$ (NC) : $\sqrt{s'} = m_{\ell\ell}$
- For $\ell\nu$ (CC) : Use transverse mass m_T instead

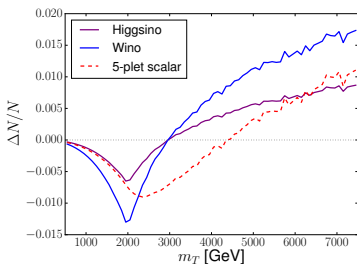
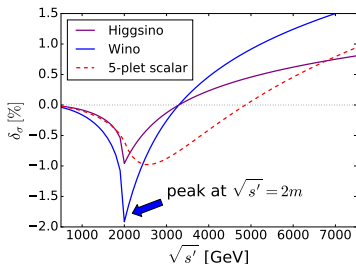
$$m_T^2 \equiv 2p_{T,\ell} p_{T,\text{miss}} (1 - \cos \phi_{T,\ell,\text{miss}}) \leq m_{\ell\nu}^2$$

($m_T \simeq m_{\ell\nu}$ if $p_{\ell,z}, p_{\nu,z}$ are small)



δ_σ as function of m_T

lv (CC) events are binned by m_T

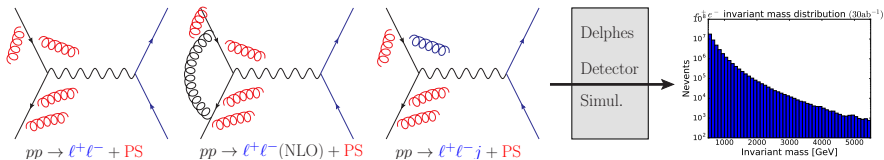


✔ Peak structure remains though smeared to lower peak height

Event generation

$\sqrt{s} = 100 \text{ TeV}$, $\mathcal{L} = 30 \text{ ab}^{-1}$ for SM, binned by $m_{\text{char}} = m_{\ell\ell}, m_T$

- MadGraph5_aMC@NLO : hard process @ NLO
- Pythia8 : parton shower (PS), hadronization
- Delphes3 : detector simulation



EWIMP effect is included by rescaling

$$N_{\text{SM}+\text{EWIMP}} = \sum_{\text{events}}^{N_{\text{SM}}} \left[1 + \delta_{\sigma}^{ab}(\sqrt{s'}) \right]$$

Event generation in detail

EWIMP effect can be included with $\delta_\sigma^{ab}(m_{\ell\ell})$

Number of events \tilde{x}_i in i -th bin $m_{\ell\ell}^{\min} < m_{\ell\ell} < m_{\ell\ell}^{\max}$

For SM,
$$\tilde{x}_i = \sum_{m_{\ell\ell}^{\min} < m_{\ell\ell}^{\text{obs}} < m_{\ell\ell}^{\max}} 1$$

For SM + EWIMP,
$$\tilde{x}_i = \sum_{m_{\ell\ell}^{\min} < m_{\ell\ell}^{\text{obs}} < m_{\ell\ell}^{\max}} \left[1 + \delta_\sigma^{ab}(m_{\ell\ell}^{\text{true}}) \right]$$

Each event in SM data set has $\{m_{\ell\ell}^{\text{obs}}, m_{\ell\ell}^{\text{true}}, a, b\}$

- $m_{\ell\ell}^{\text{obs}}$: observed $m_{\ell\ell}$ from Delphes3 output
- $m_{\ell\ell}^{\text{true}}$: true $m_{\ell\ell}$ from MadGraph5_aMC@NLO output
- a, b : initial partons from MadGraph5_aMC@NLO output

* Detector effect causes $m_{\ell\ell}^{\text{obs}} \neq m_{\ell\ell}^{\text{true}}$

Statistical treatment in our analysis

$$x_i(\mu) \equiv \sum_{\text{events}} \left[1 + \mu \delta_{\sigma}^{ab}(m_{\text{char}}) \right] \quad ; \quad \tilde{x}_i(\boldsymbol{\theta}, \mu) \equiv x_i(\mu) f_i(\boldsymbol{\theta})$$

Definition of q_0 in fitting based analysis

Wilk '38

$$q_0 = -2 \ln \frac{L(\check{\mathbf{x}}; \hat{\boldsymbol{\theta}}, \mu = 0)}{L(\check{\mathbf{x}}; \hat{\boldsymbol{\theta}}, \hat{\mu})} \sim \chi^2(1)$$

$$L(\check{\mathbf{x}}; \boldsymbol{\theta}, \mu) \equiv \prod_i \exp \left[-\frac{(\check{x}_i - \tilde{x}_i(\boldsymbol{\theta}, \mu))^2}{2\tilde{x}_i(\boldsymbol{\theta}, \mu)} \right] \prod_{\alpha} \exp \left[-\frac{\theta_{\alpha}^2}{2\sigma_{\alpha}^2} \right]$$

$\hat{\boldsymbol{\theta}}$ maximizes numerator $L(\check{\mathbf{x}}; \hat{\boldsymbol{\theta}}, \mu = 0)$

$\{\hat{\boldsymbol{\theta}}, \hat{\mu}\}$ maximizes denominator $L(\check{\mathbf{x}}; \hat{\boldsymbol{\theta}}, \hat{\mu})$

Within our analysis, $\check{x} = x_i(\mu = 1)$ and

$\{\hat{\boldsymbol{\theta}}, \hat{\mu}\} = \{0, 1\}$ with $L(\check{\mathbf{x}}; \hat{\boldsymbol{\theta}}, \hat{\mu}) = 1$

Statistical treatment : (I) Fit systematic errors

Consider number of events in i -th bin of $m_{\text{char}} = m_{\ell\ell}$ or m_T

– $\mathbf{y} = \{y_i\}$: prediction for SM \dots deformed $\tilde{y}_i(\boldsymbol{\theta}) \equiv y_i f_{\text{sys},i}(\boldsymbol{\theta})$

– $\tilde{\mathbf{y}} = \{\tilde{y}_i\}$: data with **one of errors** included

List of errors considered

- Luminosity $\pm 5\%$
- Beam energy $\pm 1\%$
- Renormalization scale $2Q, Q/2$
- Factorization scale $2Q, Q/2$
- PDF choice (101 variants of NNPDF2.3QED $\alpha_s(M_Z) = 0.118$)

Perform chi-squared fit and evaluate

$$\chi^2 = \min_{\boldsymbol{\theta}} \sum_{i:\text{bin}} \frac{(\tilde{y}_i - \tilde{y}_i(\boldsymbol{\theta}))^2}{\tilde{y}_i(\boldsymbol{\theta})}$$

Statistical treatment : (II) Fit result and σ

All errors fitted well : Best fit values for $\ell\ell$ (NC)

Sources of systematic errors	θ_1	θ_2	θ_3	θ_4	θ_5
Luminosity: $\pm 5\%$	0.07	0	0	0	0
Beam energy: $\pm 1\%$	negligible				
Renormalization scale: $2Q, Q/2$	0.6	0.9	0.4	0.08	0.006
Factorization scale: $2Q, Q/2$	0.5	0.7	0.3	0.07	0.007
PDF choice	0.4	0.7	0.3	0.06	0.004
Total	0.9	1.3	0.5	0.1	0.01

Each value can be interpreted as possible size of $|\theta|$ within SM

Let's call them as " σ " ... deviation of $|\theta|$ from 0

Assuming each source is independent, take squared sum :

$$\sigma_{\alpha}^{\text{total}} = \sqrt{(\sigma_{\alpha}^{\text{lumi.}})^2 + (\sigma_{\alpha}^{\text{ren.}})^2 + (\sigma_{\alpha}^{\text{fac.}})^2 + (\sigma_{\alpha}^{\text{PDF}})^2}$$

Statistical treatment : (III) profile likelihood method

Fit function

$$f_{\text{sys},i}(\boldsymbol{\theta}) = e^{\theta_1} (1 + \theta_2 p_i) p_i^{(\theta_3 + \theta_4 \ln p_i + \theta_5 \ln^2 p_i)}$$
$$p_i = 2m_{\text{char},i} / \sqrt{s}$$

Definition of test statistic q_0

$$q_0 \equiv \min_{\boldsymbol{\theta}} \left[\underbrace{\sum_{i:\text{bin}} \frac{(\check{x}_i - \tilde{x}_i(\boldsymbol{\theta}))^2}{\tilde{x}_i(\boldsymbol{\theta})}}_{\text{try to fit data}} + \underbrace{\sum_{\alpha=1}^5 \frac{\theta_{\alpha}^2}{\sigma_{\alpha}^2}}_{\text{control size of } \boldsymbol{\theta}} \right]$$

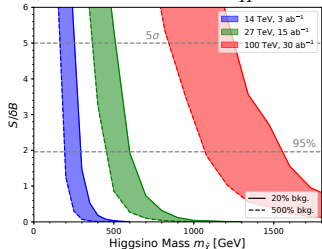
q_0 tests **validity of SM** and obeys $\chi^2(1)$

Wilk '38

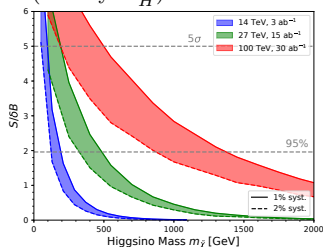
Comparison with other approaches

Higgsino production at $\sqrt{s} = 100 \text{ TeV}$, $\mathcal{L} = 30 \text{ ab}^{-1}$

- disappearing track search
(for pure Higgsino $c\tau_{\tilde{H}} \sim 1 \text{ cm}$)



- mono-jet search
(for any $c\tau_{\tilde{H}}$)



- indirect study

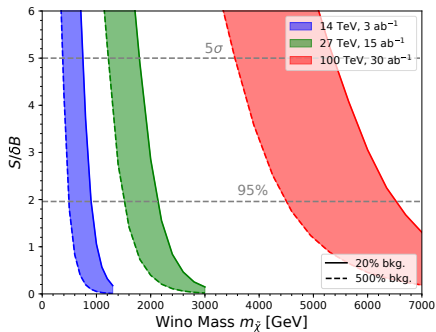
Probe $m_{\tilde{H}} < 850 \text{ GeV}$ (1.7 TeV)
at 5σ (95% C.L.) level

T. Han⁺ '18

Our method provides

- comparable reach for pure Higgsino
- better for short lifetime Higgsino

Disappearing track search of Wino



Other sources of systematic errors

Smooth correction seems to be well absorbed into θ : Then,

- estimation error in detector effect
may also be absorbed : **our method can be applied!!**

- higher order loop effect within SM
- background process
in principle possible to take account of (future task)

Yet remaining sources:

- pile-up effect
- underlying event
negligible thanks to clean signal with two energetic leptons

Statistical treatment for properties determination

Fix $\mu = 1$ (SM+EWIMP) and consider (m, C_1, C_2) dependence

$$x_i(m, C_1, C_2) \equiv \sum_{\text{events}} \left[1 + \delta_{\sigma}^{ab}(m, C_1, C_2; \sqrt{s'}) \right]$$

Assume \check{x} for 1.1 TeV Higgsino as example:

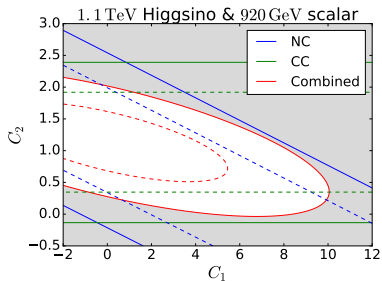
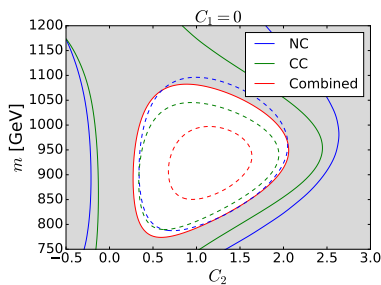
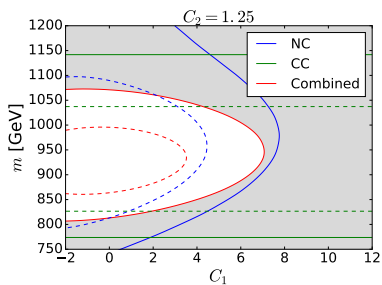
$$\check{x}_i = x_i(m = 1.1 \text{ TeV}, C_1 = 1, C_2 = 1)$$

Although still 3.5σ hint we try...

$$q(m, C_1, C_2) \equiv \min_{\theta} \left[\sum_{i:\text{bin}} \frac{(\check{x}_i - \tilde{x}_i(\theta, m, C_1, C_2))^2}{\tilde{x}_i(\theta, m, C_1, C_2)} + \sum_{\alpha=1}^5 \frac{\theta_{\alpha}^2}{\sigma_{\alpha}^2} \right]$$

q tests validity of model (m, C_1, C_2)

Determination of spin



Solid (Dotted) : 2σ (1σ)

– Best fit:

$$(m, C_1, C_2) = (920 \text{ GeV}, 0, 1.2)$$

– Bosonic EWIMP allowed

– For lighter (e.g. $m = 800 \text{ GeV}$)
Higgsino, only fermion allowed